

A CAD system for teaching digital test

Ubar, Raimund-Johannes; Ivask, Eero; Paomets, Priidu; **Raik, Jaan** BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 369-372: ill

Collaborative distributed computing in the field of digital electronics testing

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Balanced Automation Systems for Future Manufacturing Networks : 9th IFIP WG 5.5 International Conference : BASYS 2010 : Valencia, Spain, July 21-23, 2010 : proceedings 2010 / p. 145-152

Collaborative distributed fault simulation for digital electronic circuits

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Intelligent Distributed Computing IV : proceedings of the 4th International Symposium on Intelligent Distributed Computing - IDC 2010 : Tangier, Morocco, September 2010 2010 / p. 67-76

Comparison of genetic and random techniques for test pattern generation

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 163-166: ill

Defect-oriented mixed-level fault simulation in digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina Facta Universitatis [Niš]. Series electronics and energetics 2002 / 1, April, p. 123-136 : ill

Defect-oriented test generation and fault simulation in the environment of MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Gramatova, Elena; Fisherova, Maria; **Ivask, Eero; Ubar, Raimund-Johannes;** Pleskacz, Witold A.; Kuzmich, W. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 303-306 : ill

Digital design flow with test activities

Diener, Karl-Heinz; Elst, G.; **Ivask, Eero; Jervan, Gert;** Peng, Z.; **Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum 2000 / [11] p

Digital test in WEB-based environment

Ivask, Eero 2006 https://www.ester.ee/record=b2158119*est

Distributed approach for genetic test generation in the field of digital electronics

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes Intelligent Distributed Computing, Systems and Applications : proceedings of the 2nd International Symposium on Intelligent Distributed Computing : IDC 2008 : Catania, Italy, 2008 2008 / p. 127-136

Distributed approach for parallel exact critical path tracing fault simulation

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes MIXDES 2010 : 17th International Conference "Mixed Design of Integrated Circuits and Systems" : June 24-26, 2010, Wroclaw, Poland 2010 / p. 471-476 : ill

Distributed approach for parallel exact critical path tracing fault simulation

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes International journal of microelectronics and computer science 2010 / p. 165-174 : ill

Distributed fault simulation with collaborative load balancing for VLSI circuits

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Scalable computing : practice and experience 2011 / p. 153-163 : ill

Fault oriented test pattern generation for sequential circuits using Genetic Algorithms

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 129-132 : ill

Fault oriented test pattern generation for sequential circuits using genetic algorithms

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes IEEE European Test Workshop 2000 / p. 319-320

FPGA design flow with automated test generation

Elst, G.; Diener, Karl-Heinz; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** Proc. of German 11th Workshop on Test Technology and Reliability of Circuits and Systems : Potsdam, 1999 1999 / p. 120-123
<https://masters.donntu.ru/2010/fknt/masyakin/library/article7.pdf>

GA-based test generation for sequential circuits

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes; Ivask, Eero Proceedings of East-West Design & Test Workshop (EWDTW'04) : Yalta, Alushta, Crimea, Ukraine, September 23-26, 2004 2004 / p. 30-34

Geneetilisid algoritmid

Ivask, Eero A & A 1999 / 1, lk. 33-39: ill

Hierarchical fault simulation in digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina International Symposium on Signals, Circuits and Systems : SCS 2001 : July 10-11, 2001, Iasi, Romania : proceedings 2001 / p. 181-184 : ill

Improved VHDL input for high-level synthesis tool xTractor

Ellervee, Peeter; Ivask, Eero; Kruus, Margus BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 87-90 : ill

Integrated design and test generation under Internet based environment MOSCITO

Schneider, Andre; **Ivask, Eero; Ubar, Raimund-Johannes** Euromicro Symposium on Digital System Design : Architectures, Methods and Tools : September 4-6, 2002, Dortmund, Germany : proceedings 2002 / p. 187-194 : ill
<http://dx.doi.org/10.1109/DSD.2002.1115368>

Integration of digital test tools to the internet-based environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, Günter; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** SCI 2003 : the 7th World Multiconference on Systemics, Cybernetics and Informatics : July 27-30, 2003, Orlando, Florida, USA : proceedings. Volume VIII, Applications of Informatics and Cybernetics in Science and Engineering 2003 / p. 136-141 : ill
https://www.researchgate.net/publication/250063424_Integration_of_Digital_Test_Tools_to_the_Internet-Based_Environment_MOSCITO

Internet based test generation and fault simulation

Ivask, Eero; Ubar, Raimund-Johannes; Raik, Jaan; Schneider, Andre IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 57-60 : ill

Internet-based collaborative test generation with MOSCITO [Electronic resource]

Schneider, Andre; **Ivask, Eero;** Miklos, P.; **Raik, Jaan;** Diener, Karl-Heinz; **Ubar, Raimund-Johannes;** Cibakova, Tatiana; Gramatova, Elena SIGDA publications on CD-ROM : DATE'02 : Design, Automation and Test in Europe, Paris, France, March 4-8, 2002 2002 / [6] p. [CD-ROM] https://www.cecs.uci.edu/~papers/date07/PAPERS/2002/DATE02/PDFFILES/02E_2.PDF

Internet-based testability-driven test generation in the virtual environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, G.; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** International Federation for Information Processing IFIP : International Workshop on IP-Based SoC Design 2002 : proceedings : Grenoble, October 30-31, 2002 2002 / p. 357-362 : ill <http://publica.fraunhofer.de/dokumente/N-287433.html>

Internet-basierter Systementwurf mit MOSCITO

Schneider, Andre; Schneider, Peter; Gramatova, Elena; **Ivask, Eero** Entwurf Integrierter Schaltungen : 10. E.I.S.-Workshop : Präsentationen der ITG-Fachtagung : vom 3. bis 5. April 2001 in Dresden 2001 / S. 295-296 : ill

Low-cost CAD system for teaching digital test

Ubar, Raimund-Johannes; Raik, Jaan; Paomets, Priidu; Ivask, Eero; Jervan, Gert; Markus, Antti Microelectronics education : proceedings of the European Workshop, Grenoble, France, 5-6 Feb 1996 1996 / p. 185-188

Mapping of VHDL structures for generic EDA database format IRSYD

Ivask, Eero; Ellervee, Peeter The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 317-320 : ill

Mixed-level defect simulation in data-paths of digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina 23rd International Conference on Microelectronics : MIEL 2002, Niš, Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 617-620 : ill <https://ieeexplore.ieee.org/document/1003333>

Multi-level fault simulation of digital systems on decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina The First IEEE International Workshop on Electronic Design, Test and Applications : DELTA 2002, 29-31 January 2002, Christchurch, New Zealand : proceedings 2002 / p. 86-91 : ill

Nädal Hannoveri rahvusvahelisel tööstusmessil

Ivask, Eero; Põldre, Jüri Tehnikaülikool 1998 / 25. mai, lk. 8-9: ill

On using genetic algorithm for test generation

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes; Ivask, Eero BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 233-236 : ill

Research environment for teaching digital test

Ivask, Eero; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Synergies between Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 468-473 : ill https://pld.ttu.ee/dildis/publications/IWK'2004_res_inv.pdf

Test cover calculation in digital systems with word-level decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina Вестник Томского государственного университета 2002 / с. 315-319 : ил

Turbo tester - diagnostic package for research and training

Aarna, Margit; Ivask, Eero; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes; Vislogubov, Vladislav; Wuttke, Heinz-Dietrich Radioelectronics and informatics 2003 / p. 69-73 : ill

Web-based environment for digital electronics test tools

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes; Schneider, Andre Virtual Enterprises and collaborative networks : IFIP 18th World Computer Congress [and] TC5/WG5.5 - 5th Working Conference on Virtual Enterprises : 22-27 August 2004, Toulouse, France 2004 / p. 435-442 : ill https://link.springer.com/chapter/10.1007/1-4020-8139-1_46

Web-based framework for distributed remote laboratory in the field of digital system test

Ivask, Eero; Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 182-187 : ill <http://dx.doi.org/10.1109/EAEEIE.2008.4610183>

Web-based framework for parallel distributed test [Electronic resource]

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes 2008 IEEE Design and Diagnostics of Electronic Circuits and Systems : Bratislava, Slovakia, April 16-18, 2008 2008 / p. 271-274 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4538800>

VHDL front-end for high-level synthesis tool xTractor

Ivask, Eero; Ellervee, Peeter BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 111-114 : ill

VILAB test generation tools running under the MOSCITO system

Schneider, Andre; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum : Győr, Hungary, 2001 2001 / [12] p